Search Notes ‖‖‖‖‖‖‖	Application/Control No. 10725378	Applicant(s)/Patent Under Reexamination FAN ET AL.
	Examiner PETER COUGHLAN	Art Unit 2129

SEARCHED

Class	Subclass	Date	Examiner
706	@pd<20031203 and 8, 16, 45, 49	11/2/2007	PDC
703	@pd<20031203 and 2, 9	11/2/2007	PDC
706	@ad<20031203 and @pd>20071102 w/45, 46, 12, 16	4/29/2008	PDC
706	@ad<20031203 and 46	7/14/2008	PDC
707	@ad<20031203 and 1, 3, 4	7/14/2008	PDC
706	Apd<20031203 with model and 12, 16, 21	12/4/2008	PDC
705	@pd<20031203 w/charity and 39	5/26/2009	PDC

SEARCH NOTES

Search Notes	Date	Examiner
East -- @pd<20031203 and inductive learning, learning model, featrure vector, aggregate benefit, application, purpose, function, Fan Wei, Wang Haixun, Yu Phillip, database, segment, subset, accuracy, predictive, time, cost, stepwise, progressive	11/2/2007	PDC
IEEE -- <2003 Fan Wei, Wang Haixun, Yu Phillip, database, subset, accuracy, predictive, time, cost, stepwise, progressive, inductive learning, learning model, feature vector, aggregae benefit, application, purpose, function	11/2/2007	PDC
Inventors -- Fan Wei, Wang Haixun, Yu Phillip	11/2/2007	PDC
Google <2003 inductive learning, learning model, feature vector, aggregae benefit, application, purpose, function, Fan Wei	11/2/2007	PDC
Dogpile Fan Wei, Wang Haixun, Yu Phillip, database, segment, subset, accuracy, predictive, time cost stepwise, progressive	11/2/2007	PDC
East -- @ad<20031203 and @pd>20071102 and dataset, subset, learning model, model, plurality w/subset, increment, divid$, database, progressive, termination, threshold, build$, combin$	4/29/2008	PDC
East -- @pd<20031203 and inductive, learning model, dividing, dataset, data, subset, model, indication w/termination, threshold, accuracy, current	12/4/2008	PDC
East -- @pd<20031203 and estimate, training, system, charity, donation, model, processor, base, classifier, calculator, accuracy, subset, data, plurality, numerous, estimate, confidence, interval, ensemble model, time, duration, period, parametric statistics	5/7/2009	PDC

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner